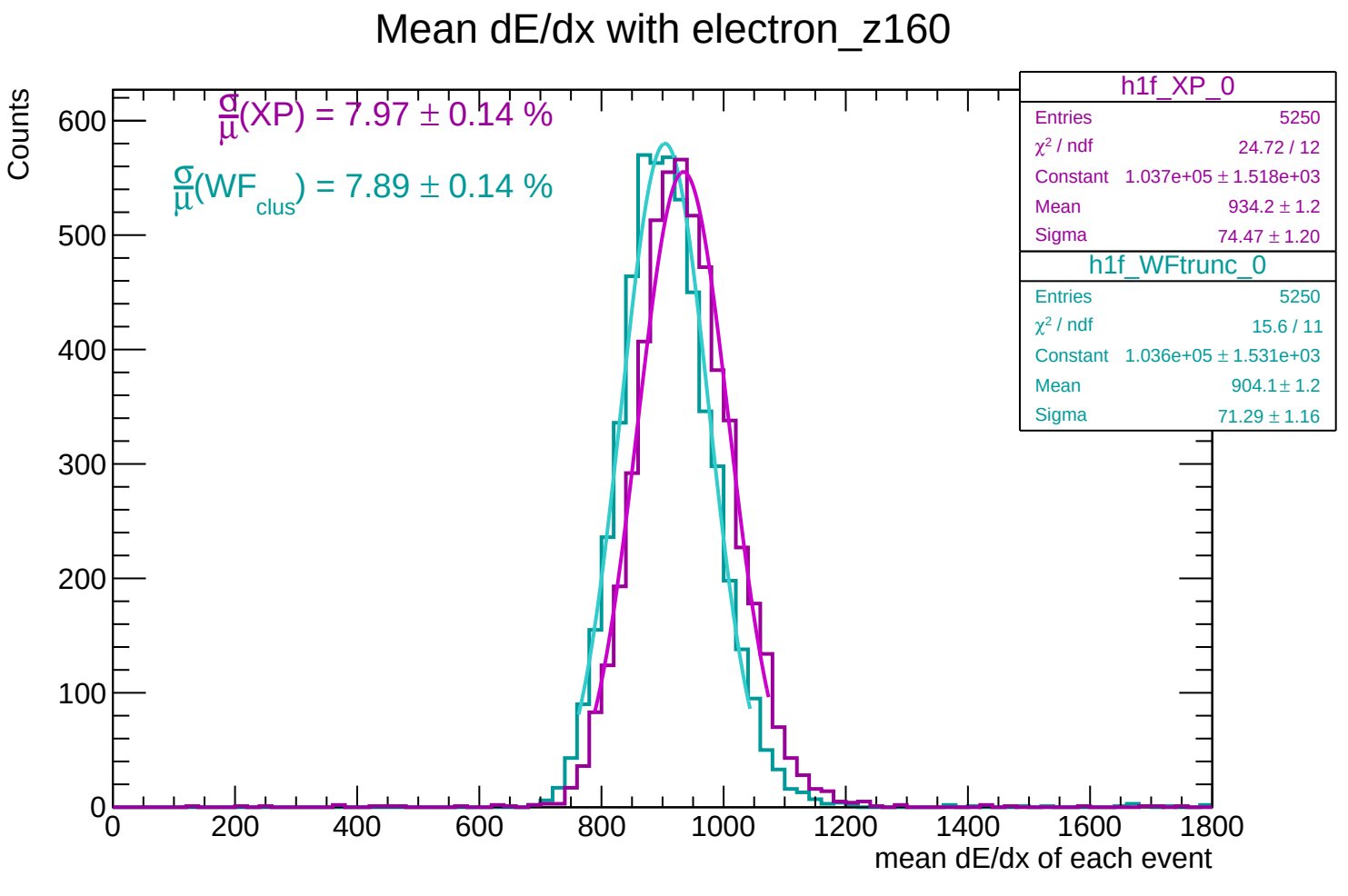
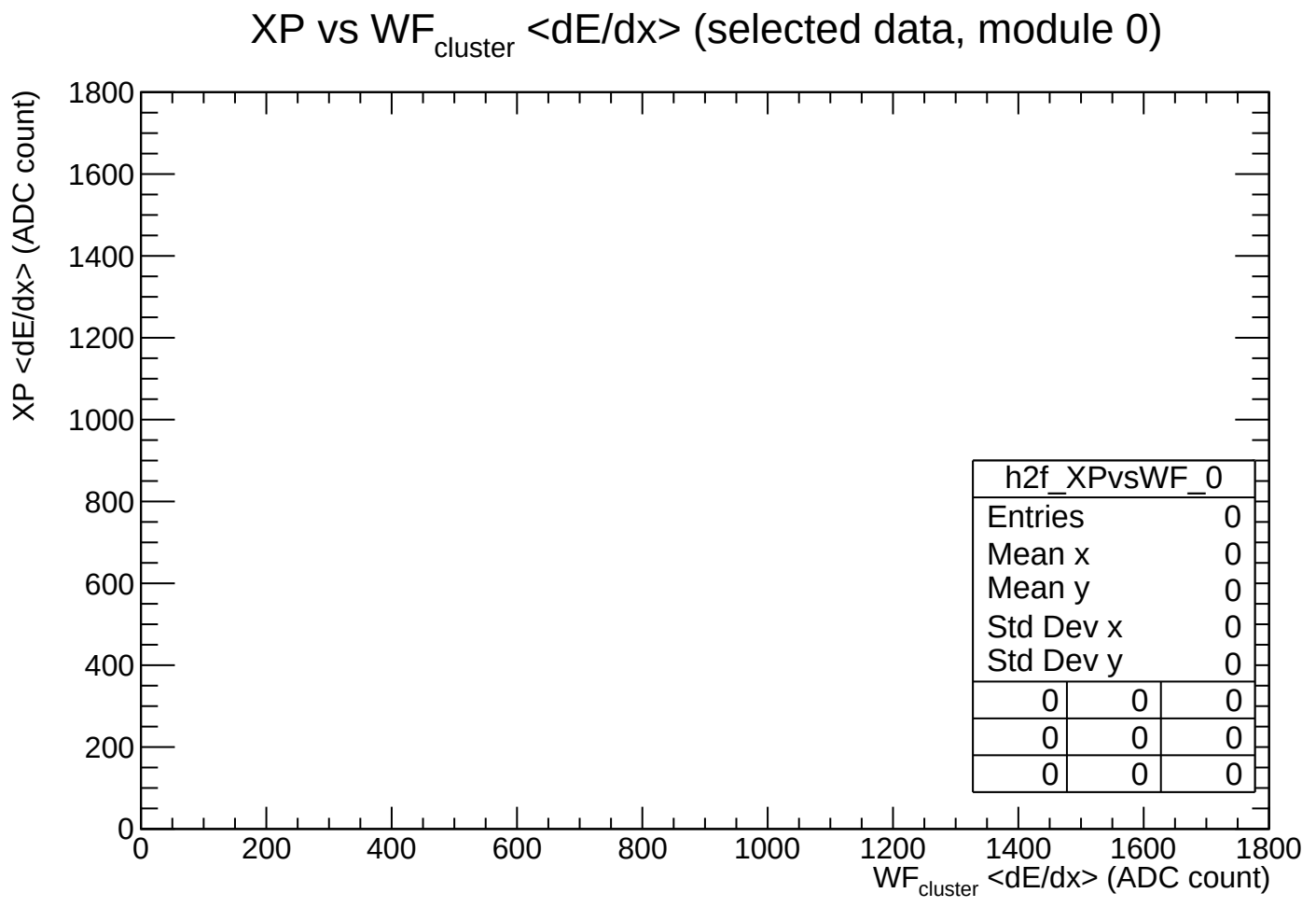
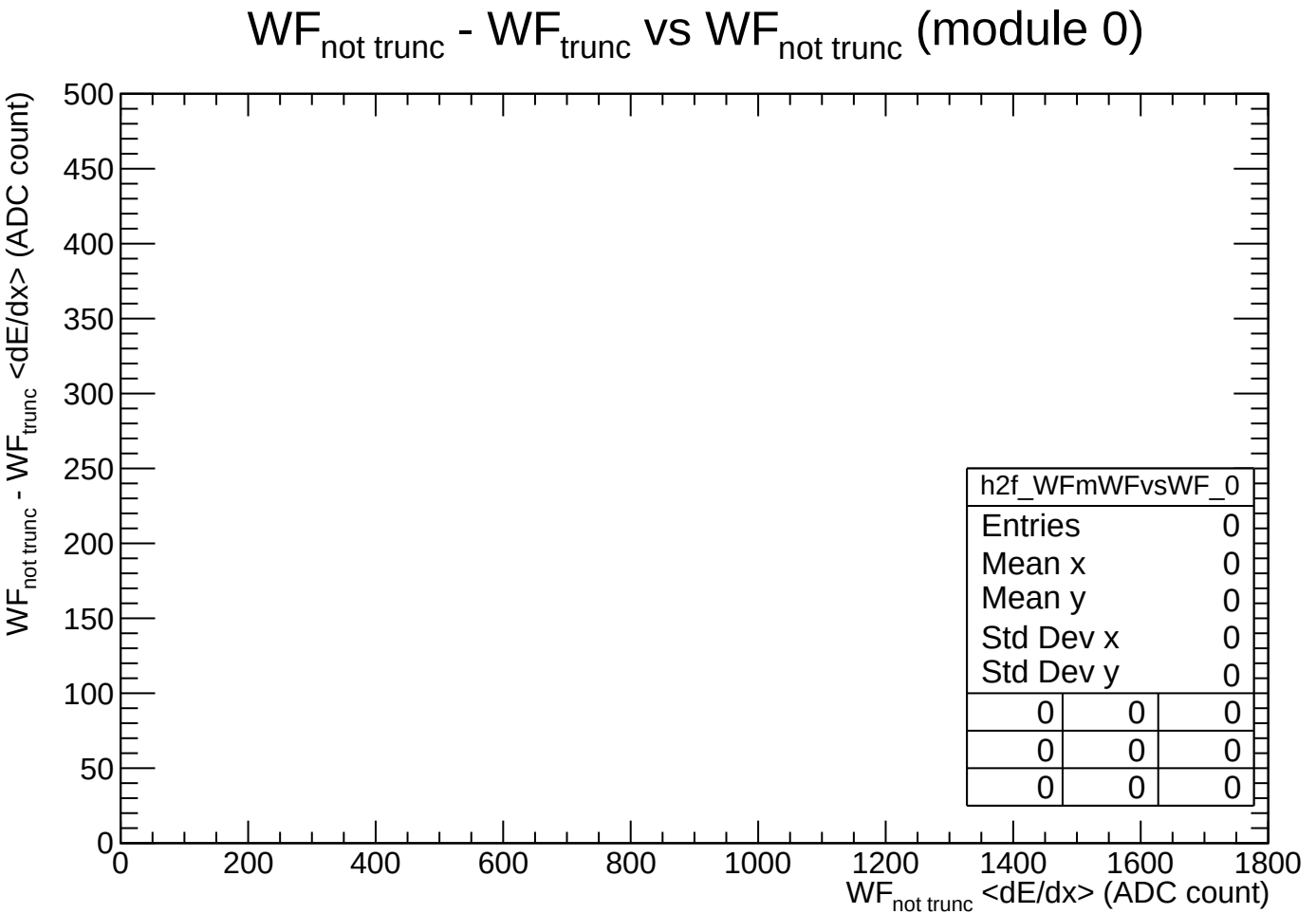

Mean dE/dx with electron_z160
Counts
mean dE/dx of each event
σ/μ(XP) = 7.97 ± 0.14 %
σ/μ(WF_clus) = 7.89 ± 0.14 %
h1f_XP_0
Entries 5250
χ² / ndf 24.72 / 12
Constant 1.037e+05 ± 1.518e+03
Mean 934.2 ± 1.2
Sigma 74.47 ± 1.20
h1f_WFtrunc_0
Entries 5250
χ² / ndf 15.6 / 11
Constant 1.036e+05 ± 1.531e+03
Mean 904.1 ± 1.2
Sigma 71.29 ± 1.16
0
100
200
300
400
500
600
0
200
400
600
800
1000
1200
1400
1600
1800


XP vs WF_cluster <dE/dx> (selected data, module 0)
XP <dE/dx> (ADC count)
WF_cluster <dE/dx> (ADC count)
0
200
400
600
800
1000
1200
1400
1600
1800
h2f_XPvsWF_0
Entries 0
Mean x 0
Mean y 0
Std Dev x 0
Std Dev y 0
0 0 0
0 0 0
0 0 0


WF not trunc - WF trunc vs WF not trunc (module 0)
WF not trunc - WF trunc <dE/dx> (ADC count)
WF not trunc <dE/dx> (ADC count)
h2f_WFmWFvsWF_0
Entries 0
Mean x 0
Mean y 0
Std Dev x 0
Std Dev y 0
0 0 0
0 0 0
0 0 0
0 50 100 150 200 250 300 350 400 450 500
0 200 400 600 800 1000 1200 1400 1600 1800